L Number	Hits	Search Text	DB	Time stamp
7	6	(test with parameter) and database and wafer and ((machine equipment) with (defect fault fail failure failing failed faulty faulted)) and (packaging with process)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/02 08:35
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9	4	((test with parameter) and database and ((machine equipment) with (defect fault fail failure failing failed faulty faulted)) and (packaging with process)) not(((test with parameter) and database and wafer and ((machine equipment) with (defect fault fail failure failing failed faulty faulted)) and (packaging with process)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/02 08:35

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